


<b>Search Notes</b>  	<b>Application/Control No.</b>  10783768	<b>Applicant(s)/Patent Under Reexamination</b>  HARPER ET AL.
	<b>Examiner</b>  Bautista, X. L.	<b>Art Unit</b>  2179

SEARCHED			
Class	Subclass	Date	Examiner
715	700,744,764,765,788,800,801,815,853	7/18/08	XB
715	200,212,217,221,225,243,246,249,255	7/18/08	XB

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	7/18/08	XB
Databases Searched:US-PGPUB; USPAT	7/18/08	XB
EPO; JPO; DERWENT; IBM_TDB	7/18/18	XB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner